Non-Contact Sheet Resistance Tester

DATA SHEET - EddyCus® TF lab 4040 series

HIGHLIGHTS
- Contact-free & real-time
- Accurate single-point measurement of sheet resistance for conductive thin films (Ohm/sq)
- Layer thickness measurement of metal films (nm)
- Layer and substrate thickness monitoring (µm)
- Characterization of multilayer systems on request
- Manual mapping of sheet resistance guided by an easy-to-handle software

APPLICATIONS
> Architectural glass (LowE)
> Touch screens & flat monitors
> OLED & LED applications
> Smart-glass applications
> Transparent antistatic foils
> Photovoltaics
> Semiconductors
> De-icing & heating applications
> Batteries & fuel cells
> Packaging materials
DATA SHEET

EddyCus® TF lab 4040 series – Sheet Resistance Tester

<table>
<thead>
<tr>
<th>Feature</th>
<th>Details</th>
</tr>
</thead>
<tbody>
<tr>
<td>Sheet resistance measurement technology</td>
<td></td>
</tr>
<tr>
<td>Substrates</td>
<td></td>
</tr>
<tr>
<td>Substrate area</td>
<td></td>
</tr>
<tr>
<td>Max. sample thickness/sensor gap (defines distances)</td>
<td></td>
</tr>
<tr>
<td>Sheet resistance range</td>
<td></td>
</tr>
<tr>
<td>Thickness measurement of thin films (e.g. copper)</td>
<td></td>
</tr>
<tr>
<td>Device dimension (w/h/d)</td>
<td></td>
</tr>
<tr>
<td>Weight</td>
<td></td>
</tr>
<tr>
<td>Available features</td>
<td></td>
</tr>
</tbody>
</table>

Non-contact eddy current sensor

e.g. foil, glass and wafer

29.5 x 25.6 inch/ 750 x 650 mm
(for measurement of 16 inch / 400 x 400 mm samples)

Max. sample thickness/sensor gap (defined by the thickest sample/application)

1 / 2 / 5 / 10 / 25 mm

Sheet resistance range

- 0.0001 – 10 Ohm/sq; 2 % accuracy & 1 % repeatability
- 10 – 100 Ohm/sq; 3 % accuracy & 1.5 % repeatability
- 100 – 500 Ohm/sq; 4 % accuracy & 2 % repeatability
- 100 – 1,000 Ohm/sq; 5 % accuracy & 2.5 % repeatability
- 1,000 – 3,000 Ohm/sq; 8 % accuracy & 4 % repeatability

Thickness measurement of thin films (e.g. copper)

2 nm – 2 mm (in accordance with sheet resistance)

Device dimension (w/h/d)

30 x 12 x 26 inch / 760 x 310 x 660 mm

Weight

20 kg

Available features:
- Metal thickness measurement
- Sheet resistance anisotropy sensor
- Optical transparency

SOFTWARE & HANDLING – EddyCus® TF lab Control

Sheet resistance measurement technology

Substrates

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